



PTO/SB/08 Equivalent

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

(Multiple sheets used when necessary) SHEET 1 OF 1	Application No.	10/657,416
	Filing Date	September 8, 2003
	First Named Inventor	Naoto TSUJI, et al.
	Art Unit	2813
	Examiner	William C. Vesperman
	Attorney Docket No.	ASMJP.134AUS

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
TSJ	1.	6,374,770 B1	04/23/2002	Peter W. LEE, et al.	
	2.	6,383,917 B1	05/07/2002	Neal J. COX	
	3.	2002/0106891A1	08/08/2002	Jae-Hak KIM, et al.	
TSJ	4.	2003/042605 A1	03/06/2003	Ebrahim ANDIDEH, et al.	

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
TSJ	5.	WO 99/55526 A	11/04/1999	Peter ROSE, et al.		
	6.	EP 1 122 770 A2	08/08/2001	Atsushi SHIOTA, et al.		
	7.	EP 1 148 539 A2	10/24/2001	Tzu-Fang HUANG, et al.		
TSJ	8.	EP 1 201 795 A1	05/02/2002	Srinivas D. NEMANI, et al.		

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
TSJ	9.	Hean Ju LEE, et al., "The mechanical properties of the SiOC(-H) composite thin films with a low dielectric constant" SURFACE & COATING TECHNOLOGY, JOINT INTERNATIONAL PLASMA SYMPOSIUM OF THE 6 <sup>TH</sup> ASIA-PACIFIC CONFERENCE ON PLASMA SCIENCE & TECHNOLOGY, JEJU ISLAND, SOUTH KOREA, vol. 171 no. 1-3, July 1, 2002- July 4, 2002, ELSEVIER, SWITZERLAND, pages 296, 300	

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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.